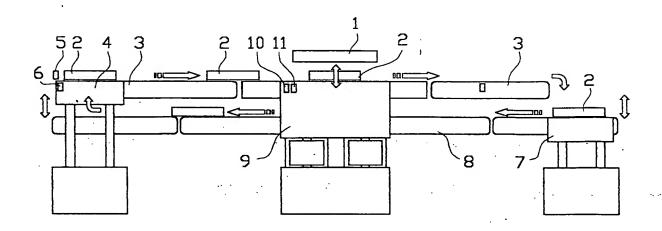
APPLN. FILING DATE: APRIL 21, 2004

[ITLE: APPARATUS AND METHOD FOR TESTING
SEMICONDUCTOR DEVICES
NVENTOR(S): TSUI, CHING MAN.
ATTY DKT. NO.: 033539-021

SHEET

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<u>FIG. 1</u>

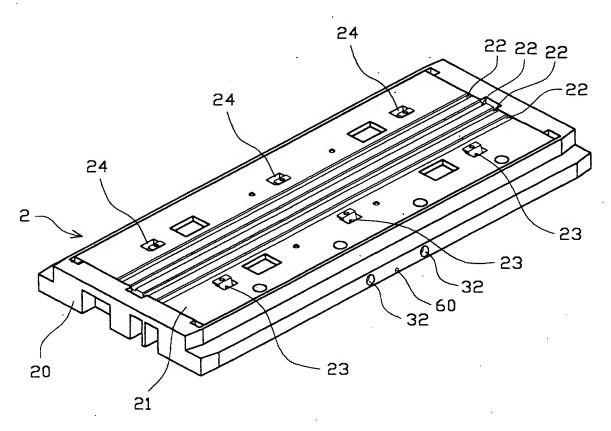


FIG.2

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SEMICONDUCTOR DEVICES
INVENTOR(S): CHING MAN TSUI ET AL.
ATTY DKT. NO.: 033539-021
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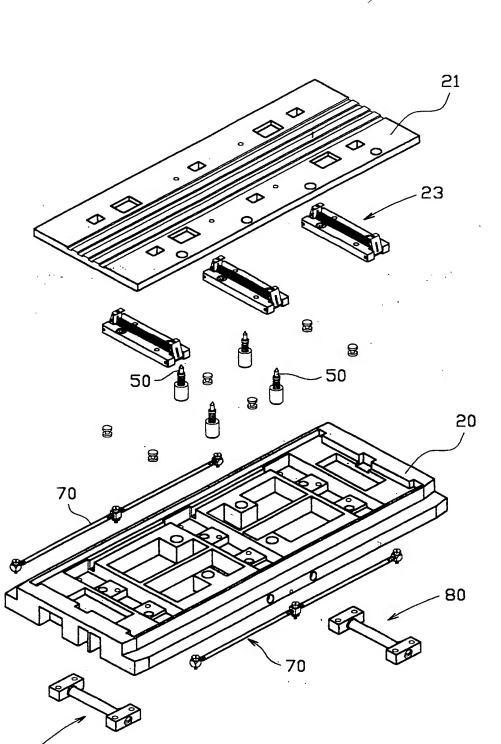
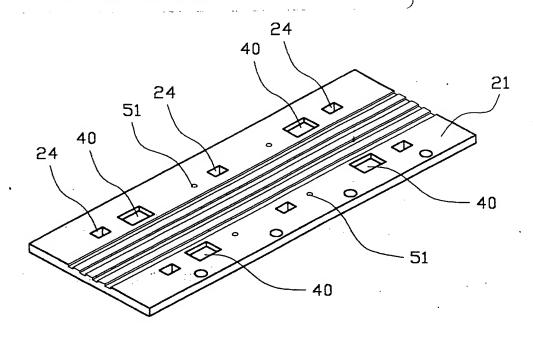


FIG.4

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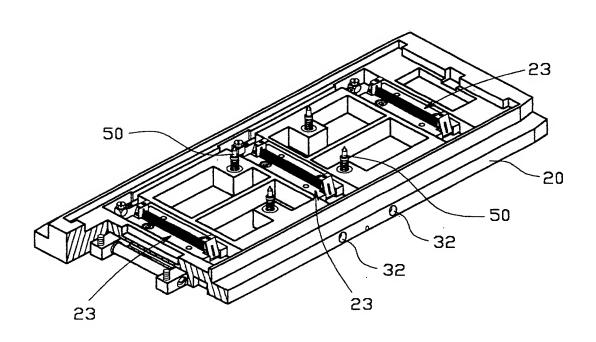


FIG.3

APPLN. FILING DATE: APRIL 21, 2004 TITLE: APPARATUS AND METHOD FOR TESTING SEMICONDUCTOR DEVICES
INVENTOR(S): CHING MAN TSUI ET AL.
ATTY DKT. NO.: 033539-021 SHEET 4 OF 9 **A** -B-A \mathbf{B} **FIG.5** 63 20 60 61 62 CROSS SECTION A-A FIG.6 90 POGO PINS PRESSURE APPLIED SUPPORTING THE APPLIED PRESSURE FLAT LEADS SUPPORT 21 FIG. 16

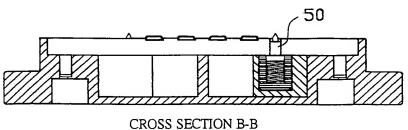


FIG.7

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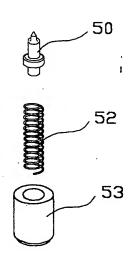


FIG.9

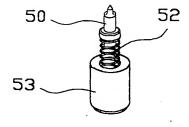


FIG.8

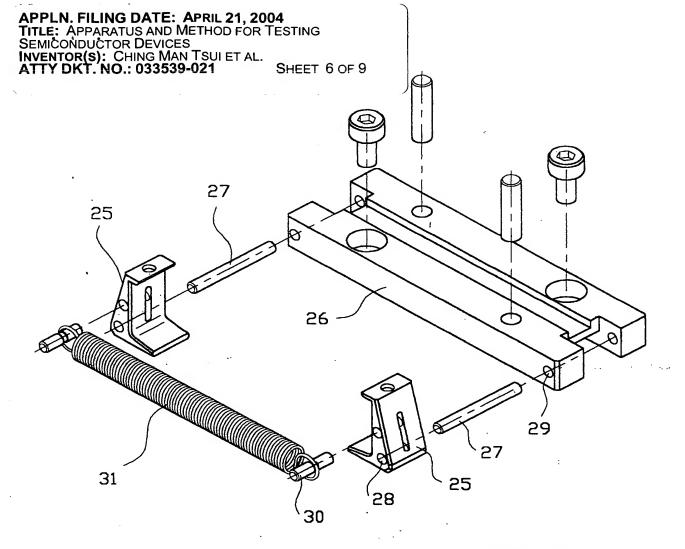


FIG. 11

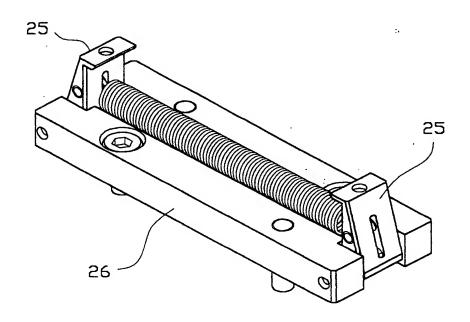


FIG.10

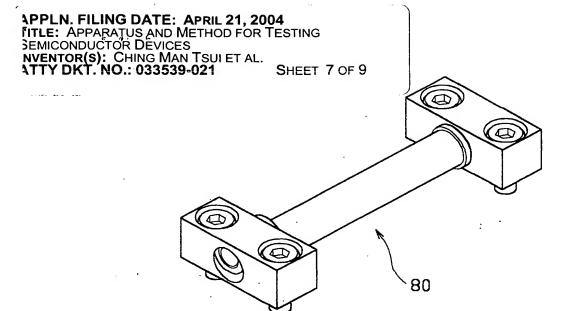
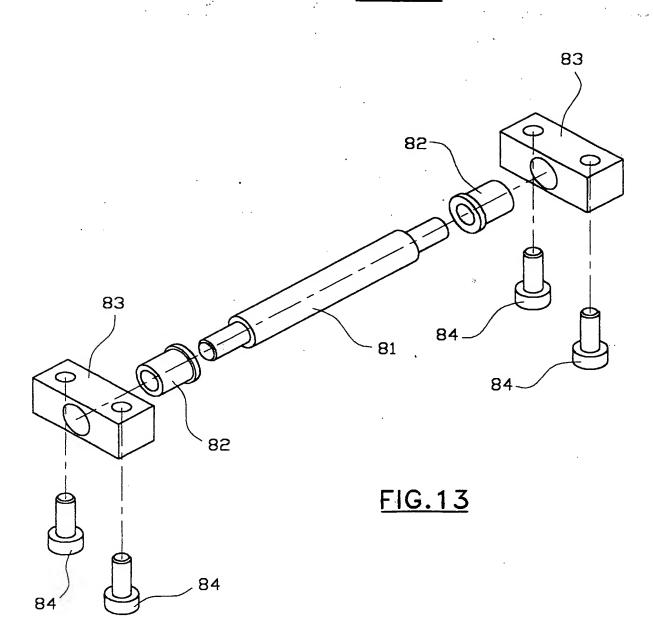
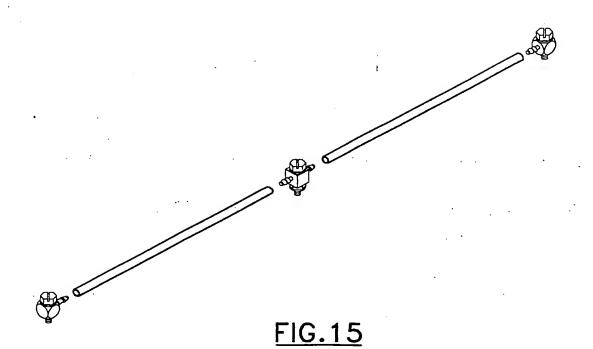


FIG. 12



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INVENTOR(S): CHING MAN TSUI ET AL.
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SHEET 8 OF 9



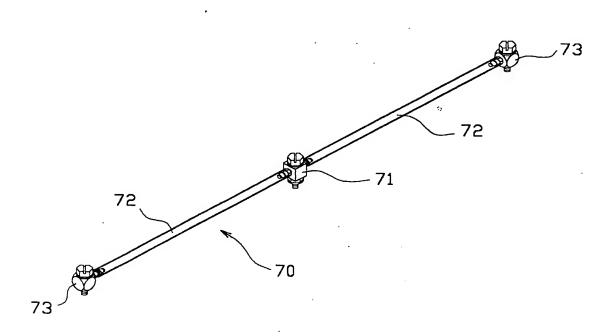


FIG.14

APPLN. FILING DATE: APRIL 21, 2004
[ITLE: APPARATUS AND METHOD FOR TESTING SEMICONDUCTOR DEVICES NVENTOR(S): CHING MAN TSUI ET AL. ATTY DKT. NO.: 033539-021 SHEET

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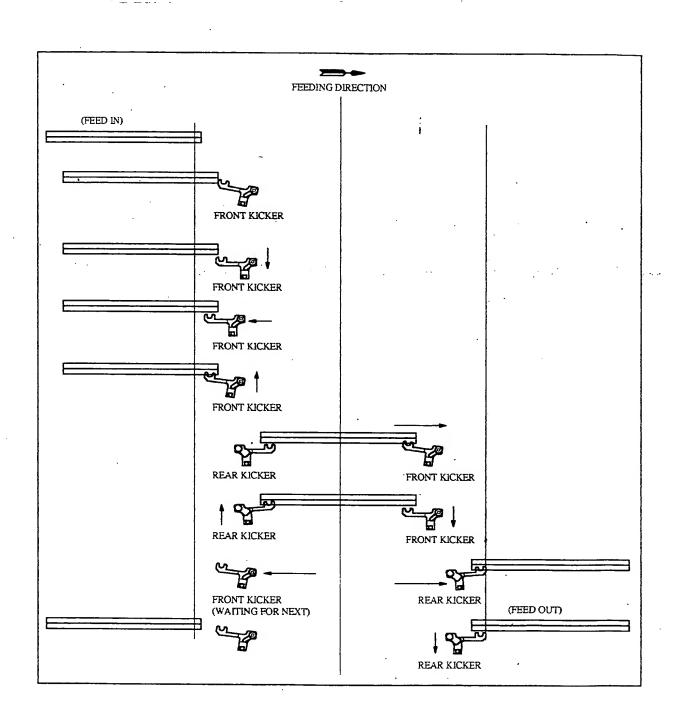


FIG. 17